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M	AA	5,21	19,788	6/93	Abernath	hoy et al.							
19	AB	5,04	45,847	9/91	Tarui et	Tarui et al.							
	AC	5,04	45,345	9/91	Singer	Singer							
	AD	4,99	96,081	2/91	Ellul et s	al.							_
	AE	3,88	84,698	5/75	Kakiham	n et al.							
	AF	5,51	18,946	5/96	Kuroda								
	AG	5,48	39,542	2/96	lwai et a	d.							
	AH	4,33	30,569	5/82	Gulett et	t al.							
	Al	4,49	99,656	2/85	Fabian et	t al.							
	LΑ	5,55	54,418	9/96	Ito et al.							:	
V	AK	5,92	26,739	7/99	Rolfson e	et al.							
W	AL	4,87	74,716	10/89	Rao								
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°	AN		137854	JP	(6/87)								
	AO	2129		GB	(5/84)								
_ V_	AP	2170)649	GB	(8/86)								
OK/	AQ	2145	5243	GB	(3/85)								
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22	AR		Silicon Proc. for VLS		•								
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av7	AS	-	Silicon Proc. for VLS	il; 191-193; Vol. 1	I; S. Wolf								
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90	АТ		Silicon Proc. for VLSI; 37-38; 598-599; Vol. 2; S. Wolf										
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	АВ	4,439,270	3/84	Powell et al.	· · ·					
	AC	5,773,325	6/98	Teramoto		. =				
	AD	5,904,523	5/99	Foldman et al.						
	AE	5,891,793	4/99	Gardner et al.						
	AF	5,795,821	8/98	Bacchetta et al.						
	AG	5,918,147	6/99	Filipiak et al.						
	AH	5,882,978	3/99	Srinivasan et al.						
	AÌ	4,612,629	9/86	Harari						
1/	AJ.	5,831,321	11/98	Nagayama						
V	AK	3,549,411	12/70	Веал	··-					
72	AL	4,446,194	5/84	Candelaria et al.		<u></u>				
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W	AQ	Electronic Materia	ls Science: For Integ	grated Circuits; 1990 ©; Mayer et al;	pp. 269-274; Pub. 1990					
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H	AR	MA; June 5-8, 19	Stitcon Nitride and 88; 1 page; Kanicki,	Silicon Dioxide Films Prepared by V J. et al.	arious Deposition Techn	iques; 1988 .	EEE Internati.	Sympos. On I	Electrical Insulation	
W	AS	Passivation of Ga 1418	AsFET's with PECV	D Silicon Nitride Films of Different	Stress States; IEEE Tran	nsactions on	Electron Device	s; Vol. 35, No	o. 9; Sept. 1913;	
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n	АА	4,485	5,553	12/84	Christian et al.					
()	AB	4,543	3,707	10/85	Ito et al.					
	AC	5,098	8,865	3/92	Machado et al					
	AD	5,160	0,998	11/92	Itoh et al.					
<u> </u>	AE	5,306	16,946	4/94	Yamamoto					
	AF	5,447	2,223	8/95	Fujii					
<u> </u>	AG	5,523	3,616	6/96	Den					
<u> </u>	АН	5,756	5,404	5/98	Friedenreich et.	Friedenreich et.				
<u> </u>	AI	5,834	4,374	11/98	Cabral Jr. et al		<u> </u>	<u> </u>		
	AJ	4,695	5,872	9/87	Chatterjee					
<u> </u>	AK	5,178	8,016	1/93	Dauenhauer et.					
192	AL	5,985	5,771	11/99	Moore et al.			<u> </u>		
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SERIAL NO. 10/769,573

APPLICANT Mark A. Helm et al.

FILING DATE January 30, 2004 **GROUP** 2826

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19	AD	6,693,345 B2	12/04	Moore et al.	257	640					
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